

54F/74F10 Triple 3-Input NAND Gate

General Description

This device contains three independent gates, each of which performs the logic NAND function.

Commercial	Military	Package Number	Package Description
74F10PC		N14A	14-Lead (0.300" Wide) Molded Dual-In-Line
	54F10DM (Note 2)	J14A	14-Lead Ceramic Dual-In-Line
74F10SC (Note 1)		M14A	14-Lead (0.150" Wide) Molded Small Outline, JEDEC
74F10SJ (Note 1)		M14D	14-Lead (0.300" Wide) Molded Small Outline, EIAJ
	54F10FM (Note 2)	W14B	14-Lead Cerpack
	54F10LM (Note 2)	E20A	20-Lead Ceramic Leadless Chip Carrier, Type C

Note 1: Devices also available in 13" reel. Use suffix = SCX and SJX.

Note 2: Military grade device with environmental and burn-in processing. Use suffix = DMQB, FMQB and LMQB.

Logic Symbol

A₀

B₀.

C0-

A₁

B₁.

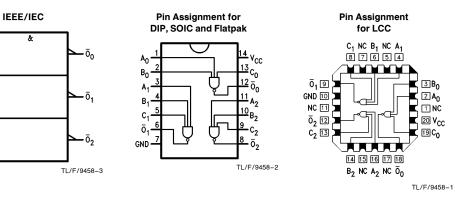
C1.

A2-

В2-

C2

Connection Diagrams



Unit Loading/Fan Out

		54F/74F			
Pin Names	Description	U.L. HIGH/LOW	Input I _{IH} /I _{IL} Output I _{OH} /I _{OL}		
A _n , B _n , C _n o n	Inputs Outputs	1.0/1.0 50/33.3	20 µA/−0.6 mA −1 mA/20 mA		

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Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	-55°C to +125°C
Junction Temperature under Bias	-55°C to +175°C
Plastic	-55°C to +150°C
V _{CC} Pin Potential to	
Ground Pin	-0.5V to $+7.0V$
Input Voltage (Note 2)	-0.5V to $+7.0V$
Input Current (Note 2)	-30 mA to $+5.0$ mA
Voltage Applied to Output	
in HIGH State (with $V_{CC} = 0V$)	
Standard Output	-0.5V to V _{CC}
TRI-STATE® Output	-0.5V to +5.5V
Current Applied to Output	
in LOW/ State (Max)	twice the rated $loc(mA)$

Recommended Operating Conditions

Free Air Ambient Temperature

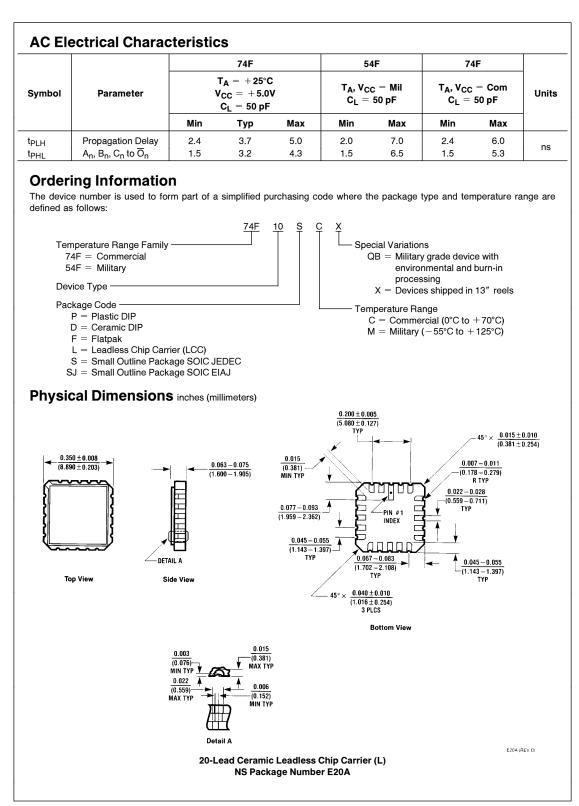
-55°C to +125°C
0°C to +70°C
+4.5V to +5.5V
+4.5V to +5.5V

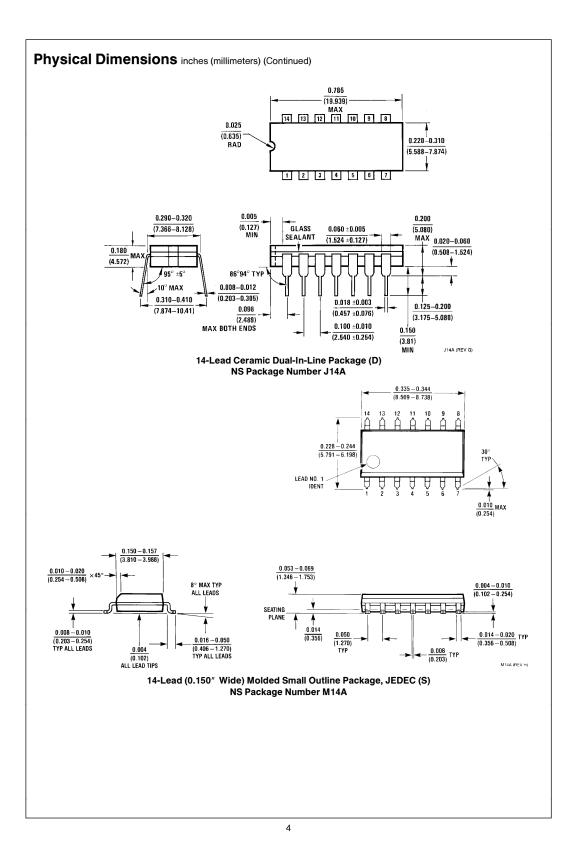
in LOW State (Max) twice the rated I_{OL} (mA) Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

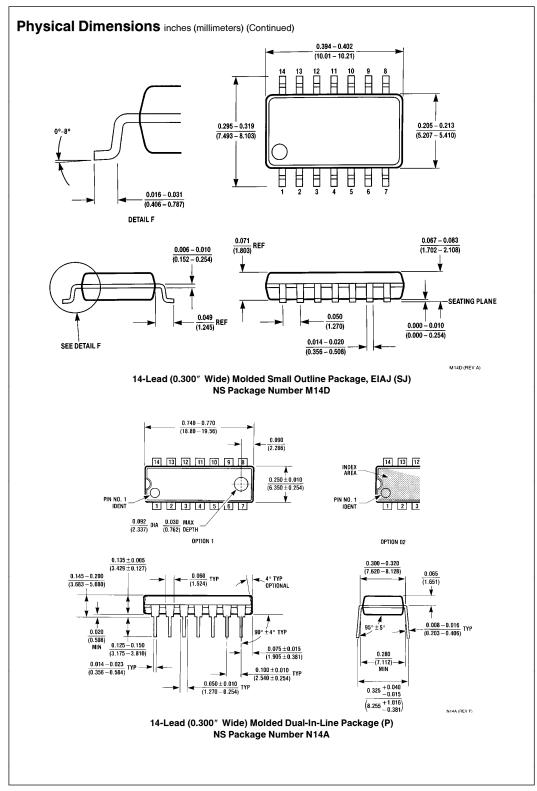
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

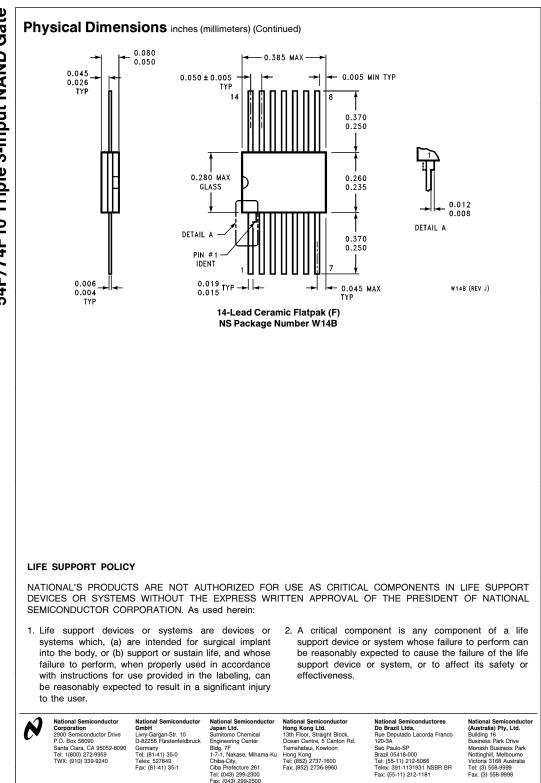
DC Electrical Characteristics

Symbol	Parameter		54F/74F			Units	Vcc	Conditions
Symbol			Min	Тур	Max	Units	vcc	Conditions
V _{IH}	Input HIGH Voltage	2.0			V		Recognized as a HIGH Sign	
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signa
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	$I_{IN} = -18 \text{ mA}$
V _{OH}	Output HIGH Voltage	54F 10% V _{CC} 74F 10% V _{CC} 74F 5% V _{CC}	2.5 2.5 2.7			V	Min	$I_{OH} = -1 \text{ mA}$ $I_{OH} = -1 \text{ mA}$ $I_{OH} = -1 \text{ mA}$
V _{OL}	Output LOW Voltage	54F 10% V _{CC} 74F 10% V _{CC}			0.5 0.5	V	Min	$I_{OL} = 20 \text{ mA}$ $I_{OL} = 20 \text{ mA}$
IIH	Input HIGH Current	54F 74F			20.0 5.0	μΑ	Max	$V_{IN} = 2.7V$
I _{BVI}	Input HIGH Current Breakdown Test	54F 74F			100 7.0	μΑ	Max	V _{IN} = 7.0V
ICEX	Output HIGH Leakage Current	54F 74F			250 50	μΑ	Max	$V_{OUT} = V_{CC}$
V _{ID}	Input Leakage Test	74F	4.75			V	0.0	$I_{ID} = 1.9 \mu A$ All other pins grounded
I _{OD}	Output Leakage Circuit Current	74F			3.75	μΑ	0.0	V _{IOD} = 150 mV All other pins grounded
IIL	Input LOW Current				-0.6	mA	Max	$V_{IN} = 0.5V$
l _{OS}	Output Short-Circuit Current		-60		-150	mA	Max	$V_{OUT} = 0V$
I _{CCH}	Power Supply Current			1.4	2.1	mA	Max	V _O = HIGH
I _{CCL}	Power Supply Current			5.1	7.7	mA	Max	$V_{O} = LOW$









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